

TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC74VCX573FT, TC74VCX573FK

Low-Voltage Octal D-Type Latch with 3.6 V Tolerant Inputs and Outputs

The TC74VCX573 is a high performance CMOS octal D-type latch which is guaranteed to operate from 1.2-V to 3.6-V. Designed for use in 1.5V, 1.8 V, 2.5 V or 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

It is also designed with over voltage tolerant inputs and outputs up to 3.6 V.

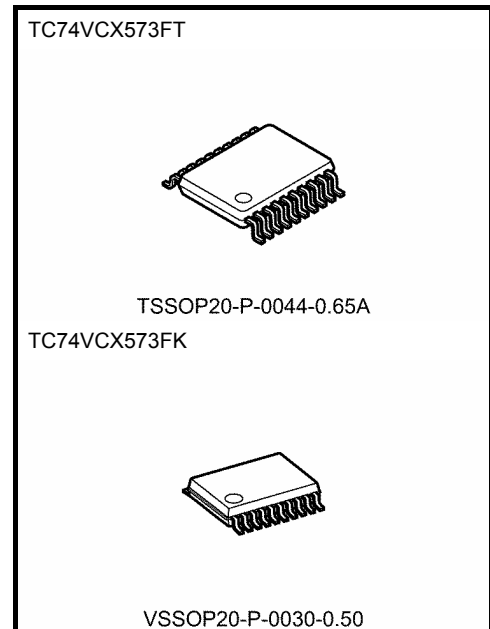
This 8 bit D-type latch is controlled by a latch enable input (LE) and an output enable input ( $\overline{OE}$ ).

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

All inputs are equipped with protection circuits against static discharge.

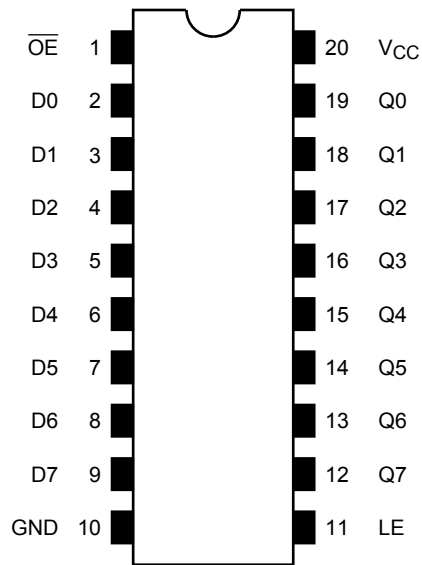
## Features

- Low voltage operation:  $V_{CC} = 1.2 \sim 3.6$  V
- High speed operation:  $t_{pd} = 4.2$  ns (max) ( $V_{CC} = 3.0 \sim 3.6$  V)  
 $t_{pd} = 4.7$  ns (max) ( $V_{CC} = 2.3 \sim 2.7$  V)  
 $t_{pd} = 9.4$  ns (max) ( $V_{CC} = 1.65 \sim 1.95$  V)  
 $t_{pd} = 18.8$  ns (max) ( $V_{CC} = 1.4 \sim 1.6$  V)  
 $t_{pd} = 47.0$  ns (max) ( $V_{CC} = 1.2$  V)
- 3.6 V tolerant inputs and outputs.
- Output current:  $I_{OH}/I_{OL} = \pm 24$  mA (min) ( $V_{CC} = 3.0$  V)  
 $I_{OH}/I_{OL} = \pm 18$  mA (min) ( $V_{CC} = 2.3$  V)  
 $I_{OH}/I_{OL} = \pm 6$  mA (min) ( $V_{CC} = 1.65$  V)  
 $I_{OH}/I_{OL} = \pm 2$  mA (min) ( $V_{CC} = 1.4$  V)
- Latch-up performance:  $-300$  mA
- ESD performance: Machine model  $\geq \pm 200$  V  
Human body model  $\geq \pm 2000$  V
- Package: TSSOP and VSSOP (US)
- Power down protection is provided on all inputs and outputs.

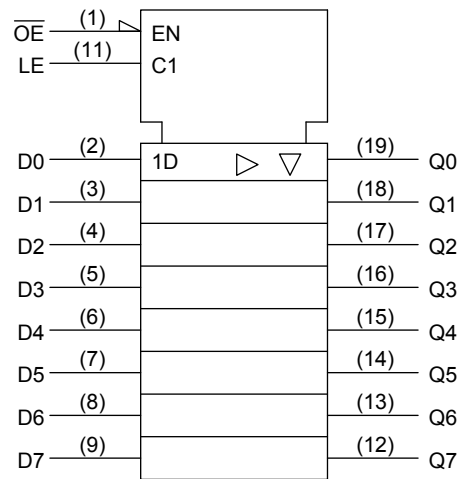


Weight	
TSSOP20-P-0044-0.65A	: 0.08 g (typ.)
VSSOP20-P-0030-0.50	: 0.03 g (typ.)

## Pin Assignment (top view)



## IEC Logic Level



## Truth Table

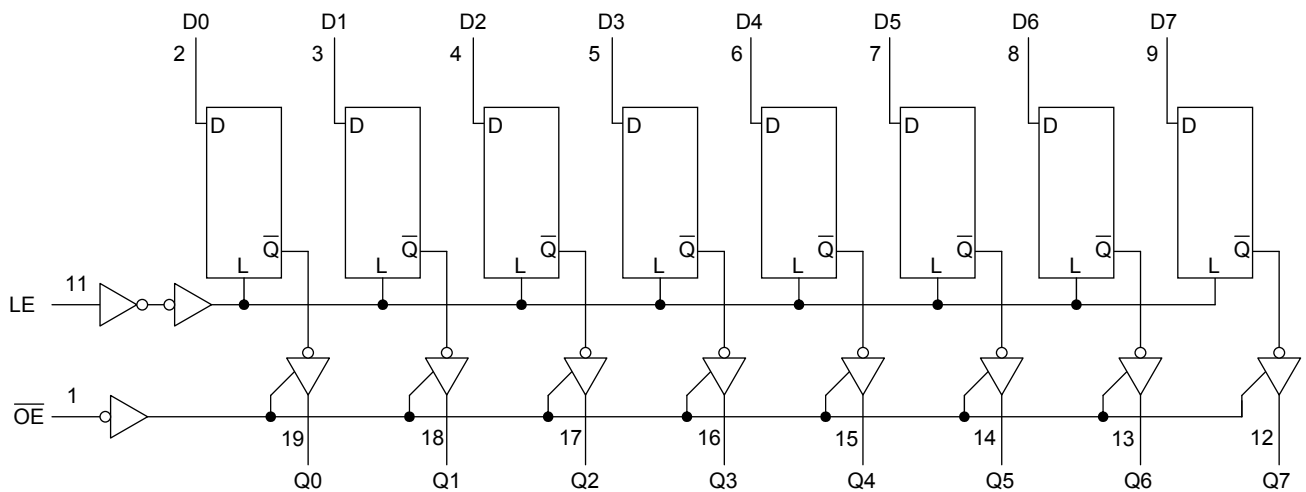
Inputs			Outputs
$\overline{OE}$	LE	D	
H	X	X	Z
L	L	X	Q <sub>n</sub>
L	H	L	L
L	H	H	H

X: Don't care

Z: High impedance

Q<sub>n</sub>: Q outputs are latched at the time when the LE inputs is taken to a low logic level.

## System Diagram



## Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Power supply voltage	$V_{CC}$	-0.5~4.6	V
DC input voltage	$V_{IN}$	-0.5~4.6	V
DC output voltage	$V_{OUT}$	-0.5~4.6 (Note 2)	V
		-0.5~ $V_{CC} + 0.5$ (Note 3)	
Input diode current	$I_{IK}$	-50	mA
Output diode current	$I_{OK}$	±50 (Note 4)	mA
DC output current	$I_{OUT}$	±50	mA
Power dissipation	$P_D$	180	mW
DC $V_{CC}$ /ground current	$I_{CC}/I_{GND}$	±100	mA
Storage temperature	$T_{stg}$	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Off-state

Note 3: High or low state.  $I_{OUT}$  absolute maximum rating must be observed.

Note 4:  $V_{OUT} < GND$ ,  $V_{OUT} > V_{CC}$

## Operating Ranges (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage	$V_{CC}$	1.2~3.6	V
Input voltage	$V_{IN}$	-0.3~3.6	V
Output voltage	$V_{OUT}$	0~3.6 (Note 2)	V
		0~ $V_{CC}$ (Note 3)	
Output current	$I_{OH}/I_{OL}$	±24 (Note 4)	mA
		±18 (Note 5)	
		±6 (Note 6)	
		±2 (Note 7)	
Operating temperature	$T_{opr}$	-40~85	°C
Input rise and fall time	dt/dv	0~10 (Note 8)	ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device.  
Unused inputs must be tied to either  $V_{CC}$  or  $GND$ .

Note 2: Off-state

Note 3: High or low state

Note 4:  $V_{CC} = 3.0\sim 3.6$  V

Note 5:  $V_{CC} = 2.3\sim 2.7$  V

Note 6:  $V_{CC} = 1.65\sim 1.95$  V

Note 7:  $V_{CC} = 1.4\sim 1.6$  V

Note 8:  $V_{IN} = 0.8\sim 2.0$  V,  $V_{CC} = 3.0$  V

## Electrical Characteristics

### DC Characteristics (Ta = -40~85°C, 2.7 V < VCC ≤ 3.6 V)

Characteristics		Symbol	Test Condition		VCC (V)	Min	Max	Unit
Input voltage	High level	V <sub>IH</sub>	—		2.7~3.6	2.0	—	V
	Low level	V <sub>IL</sub>	—		2.7~3.6	—	0.8	
Output voltage	High level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	2.7~3.6	V <sub>CC</sub> - 0.2	—	V
				I <sub>OH</sub> = -12 mA	2.7	2.2	—	
				I <sub>OH</sub> = -18 mA	3.0	2.4	—	
				I <sub>OH</sub> = -24 mA	3.0	2.2	—	
	Low level	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	2.7~3.6	—	0.2	
				I <sub>OL</sub> = 12 mA	2.7	—	0.4	
				I <sub>OL</sub> = 18 mA	3.0	—	0.4	
				I <sub>OL</sub> = 24 mA	3.0	—	0.55	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		2.7~3.6	—	±5.0	μA
3-state output off-state current		I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = 0~3.6 V		2.7~3.6	—	±10.0	μA
Power off leakage current		I <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	—	10.0	μA
Quiescent supply current		I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		2.7~3.6	—	20.0	μA
			V <sub>CC</sub> ≤ (V <sub>IN</sub> , V <sub>OUT</sub> ) ≤ 3.6 V		2.7~3.6	—	±20.0	
		ΔI <sub>CC</sub>	V <sub>IH</sub> = V <sub>CC</sub> - 0.6 V (per input)		2.7~3.6	—	750	

### DC Characteristics (Ta = -40~85°C, 2.3 V ≤ VCC ≤ 2.7 V)

Characteristics		Symbol	Test Condition		VCC (V)	Min	Max	Unit
Input voltage	High level	V <sub>IH</sub>	—		2.3~2.7	1.6	—	V
	Low level	V <sub>IL</sub>	—		2.3~2.7	—	0.7	
Output voltage	High level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	2.3~2.7	V <sub>CC</sub> - 0.2	—	V
				I <sub>OH</sub> = -6 mA	2.3	2.0	—	
				I <sub>OH</sub> = -12 mA	2.3	1.8	—	
				I <sub>OH</sub> = -18 mA	2.3	1.7	—	
	Low level	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	2.3~2.7	—	0.2	
				I <sub>OL</sub> = 12 mA	2.3	—	0.4	
				I <sub>OL</sub> = 18 mA	2.3	—	0.6	
				Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V	
3-state output off-state current		I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = 0~3.6 V		2.3~2.7	—	±10.0	μA
Power off leakage current		I <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	—	10.0	μA
Quiescent supply current		I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		2.3~2.7	—	20.0	μA
			V <sub>CC</sub> ≤ (V <sub>IN</sub> , V <sub>OUT</sub> ) ≤ 3.6 V		2.3~2.7	—	±20.0	

## DC Characteristics (Ta = -40~85°C, 1.65 V ≤ VCC < 2.3 V)

Characteristics		Symbol	Test Condition		VCC (V)	Min	Max	Unit
Input voltage	High level	V <sub>IH</sub>	—		1.65~2.3	0.65 × V <sub>CC</sub>	—	V
	Low level	V <sub>IL</sub>	—		1.65~2.3	—	0.2 × V <sub>CC</sub>	
Output voltage	High level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	1.65~2.3	V <sub>CC</sub> - 0.2	—	V
				I <sub>OH</sub> = -6 mA	1.65	1.25	—	
	Low level	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	1.65~2.3	—	0.2	
				I <sub>OL</sub> = 6 mA	1.65	—	0.3	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		1.65~2.3	—	±5.0	μA
3-state output off-state current		I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = 0~3.6 V		1.65~2.3	—	±10.0	μA
Power off leakage current		I <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	—	10.0	μA
Quiescent supply current		I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		1.65~2.3	—	20.0	μA
			V <sub>CC</sub> ≤ (V <sub>IN</sub> , V <sub>OUT</sub> ) ≤ 3.6 V		1.65~2.3	—	±20.0	

## DC Characteristics (Ta = -40~85°C, 1.4 V ≤ VCC < 1.65 V)

Characteristics		Symbol	Test Condition		VCC (V)	Min	Max	Unit
Input voltage	High level	V <sub>IH</sub>	—		1.4~1.65	0.65 × V <sub>CC</sub>	—	V
	Low level	V <sub>IL</sub>	—		1.4~1.65	—	0.05 × V <sub>CC</sub>	
Output voltage	High level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	1.4~1.65	V <sub>CC</sub> - 0.2	—	V
				I <sub>OH</sub> = -2 mA	1.4	1.05	—	
	Low level	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	1.4~1.65	—	0.05	
				I <sub>OL</sub> = 2 mA	1.4	—	0.35	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		1.4~1.65	—	±5.0	μA
3-state output off-state current		I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = 0~3.6 V		1.4~1.65	—	±10.0	μA
Power off leakage current		I <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	—	10.0	μA
Quiescent supply current		I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		1.4~1.65	—	20.0	μA
			V <sub>CC</sub> ≤ (V <sub>IN</sub> , V <sub>OUT</sub> ) ≤ 3.6 V		1.4~1.65	—	±20.0	

## DC Characteristics (Ta = -40~85°C, 1.2 V ≤ VCC < 1.4 V)

Characteristics		Symbol	Test Condition		VCC (V)	Min	Max	Unit
Input voltage	High level	V <sub>IH</sub>	—		1.2~1.4	0.8 × V <sub>CC</sub>	—	V
	Low level	V <sub>IL</sub>	—		1.2~1.4	—	0.05 × V <sub>CC</sub>	
Output voltage	High level	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	1.2	V <sub>CC</sub> - 0.1	—	V
	Low level	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 100 μA	1.2	—	0.05	
Input leakage current		I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		1.2	—	±5.0	μA
3-state output off-state current		I <sub>OZ</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub> V <sub>OUT</sub> = 0~3.6 V		1.2	—	±10.0	μA
Power off leakage current		I <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	—	10.0	μA
Quiescent supply current		I <sub>CC</sub>	V <sub>IN</sub> = V <sub>CC</sub> or GND		1.2	—	20.0	μA
			V <sub>CC</sub> ≧ (V <sub>IN</sub> , V <sub>OUT</sub> ) ≧ 3.6 V		1.2	—	±20.0	

## AC Characteristics (Ta = -40~85°C, Input: tr = tf = 2.0 ns) (Note 1)

Characteristics	Symbol	Test Condition	VCC (V)	Min	Max	Unit	
Propagation delay time (D-Q)	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	1.5	47.0	ns
				1.5 ± 0.1	1.0	18.8	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	1.5	9.4	
				2.5 ± 0.2	0.8	4.7	
Propagation delay time (LE-Q)	t <sub>pLH</sub> t <sub>pHL</sub>	Figure 1, Figure 2	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	1.5	49.0	ns
				1.5 ± 0.1	1.0	19.6	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	1.5	9.8	
				2.5 ± 0.2	0.8	4.9	
3-state output enable time	t <sub>pZL</sub> t <sub>pZH</sub>	Figure 1, Figure 3	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	1.5	49.0	ns
				1.5 ± 0.1	1.0	19.6	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	1.5	9.8	
				2.5 ± 0.2	0.8	5.5	
3-state output disable time	t <sub>pLZ</sub> t <sub>pHZ</sub>	Figure 1, Figure 3	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	1.5	32.5	ns
				1.5 ± 0.1	1.0	13.0	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	1.5	6.5	
				2.5 ± 0.2	0.8	3.6	
Minimum pulse width	t <sub>w(H)</sub>	Figure 1, Figure 2	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	24	—	ns
				1.5 ± 0.1	8.0	—	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	4.0	—	
				2.5 ± 0.2	1.5	—	
Minimum set-up time	t <sub>s</sub>	Figure 1, Figure 2	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	20	—	ns
				1.5 ± 0.1	7.5	—	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	2.5	—	
				2.5 ± 0.2	1.5	—	
Minimum hold time	t <sub>h</sub>	Figure 1, Figure 2	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	8.0	—	ns
				1.5 ± 0.1	3.0	—	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	1.0	—	
				2.5 ± 0.2	1.0	—	
Output to output skew	t <sub>osLH</sub> t <sub>osHL</sub>	(Note 2)	C <sub>L</sub> = 15 pF, R <sub>L</sub> = 2 kΩ	1.2	—	1.5	ns
				1.5 ± 0.1	—	1.5	
			C <sub>L</sub> = 30 pF, R <sub>L</sub> = 500 Ω	1.8 ± 0.15	—	0.5	
				2.5 ± 0.2	—	0.5	
				3.3 ± 0.3	—	0.5	

Note 1: For C<sub>L</sub> = 50 pF, add approximately 300 ps to the AC maximum specification.

Note 2: This parameter is guaranteed by design. (t<sub>osLH</sub> = |t<sub>pLHm</sub> - t<sub>pLHn</sub>|, t<sub>osHL</sub> = |t<sub>pHLm</sub> - t<sub>pHLn</sub>|)

## Dynamic Switching Characteristics (Ta = 25°C, Input: tr = tf = 2.0 ns, CL = 30 pF)

Characteristics	Symbol	Test Condition	VCC (V)	Typ.	Unit
Quiet output maximum dynamic VOL	VOLP	VIH = 1.8 V, VIL = 0 V (Note)	1.8	0.25	V
		VIH = 2.5 V, VIL = 0 V (Note)	2.5	0.6	
		VIH = 3.3 V, VIL = 0 V (Note)	3.3	0.8	
Quiet output minimum dynamic VOL	VOLV	VIH = 1.8 V, VIL = 0 V (Note)	1.8	-0.25	V
		VIH = 2.5 V, VIL = 0 V (Note)	2.5	-0.6	
		VIH = 3.3 V, VIL = 0 V (Note)	3.3	-0.8	
Quiet output minimum dynamic VOH	VOHV	VIH = 1.8 V, VIL = 0 V (Note)	1.8	1.5	V
		VIH = 2.5 V, VIL = 0 V (Note)	2.5	1.9	
		VIH = 3.3 V, VIL = 0 V (Note)	3.3	2.2	

Note: This parameter is guaranteed by design.

## Capacitive Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	VCC (V)	Typ.	Unit
Input capacitance	CIN	—	1.8, 2.5, 3.3	6	pF
Output capacitance	CO	—	1.8, 2.5, 3.3	7	pF
Power dissipation capacitance	CPD	fIN = 10 MHz (Note)	1.8, 2.5, 3.3	20	pF

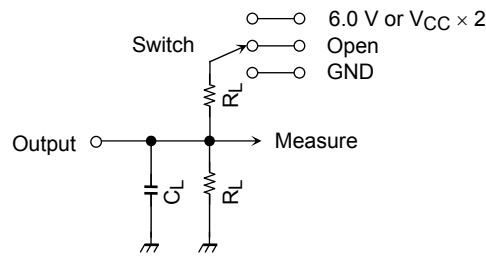
Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8 \text{ (per bit)}$$



## AC Test Circuit



Parameter	Switch
$t_{pLH}$ , $t_{pHL}$	Open
$t_{pLZ}$ , $t_{pZL}$	6.0 V $V_{CC} \times 2$ @ $V_{CC} = 3.3 \pm 0.3$ V @ $V_{CC} = 2.5 \pm 0.2$ V @ $V_{CC} = 1.8 \pm 0.15$ V @ $V_{CC} = 1.5 \pm 0.1$ V @ $V_{CC} = 1.2$ V
$t_{pHZ}$ , $t_{pZH}$	GND

Symbol	$V_{CC}$	
	$3.3 \pm 0.3$ V $2.5 \pm 0.2$ V $1.8 \pm 0.15$ V	$1.5 \pm 0.1$ V 1.2 V
$R_L$	500 $\Omega$	2k $\Omega$
$C_L$	30pF	15pF

Figure 1

## AC Waveform

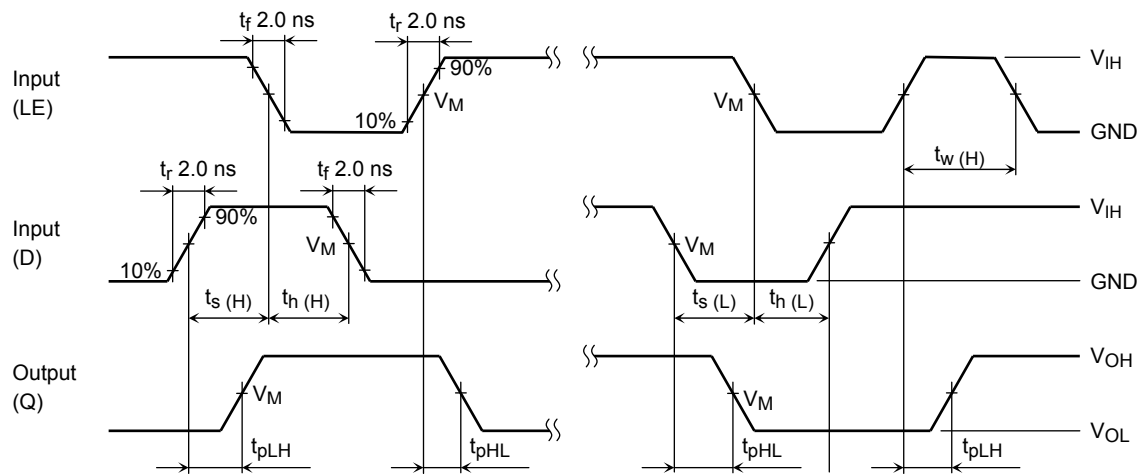
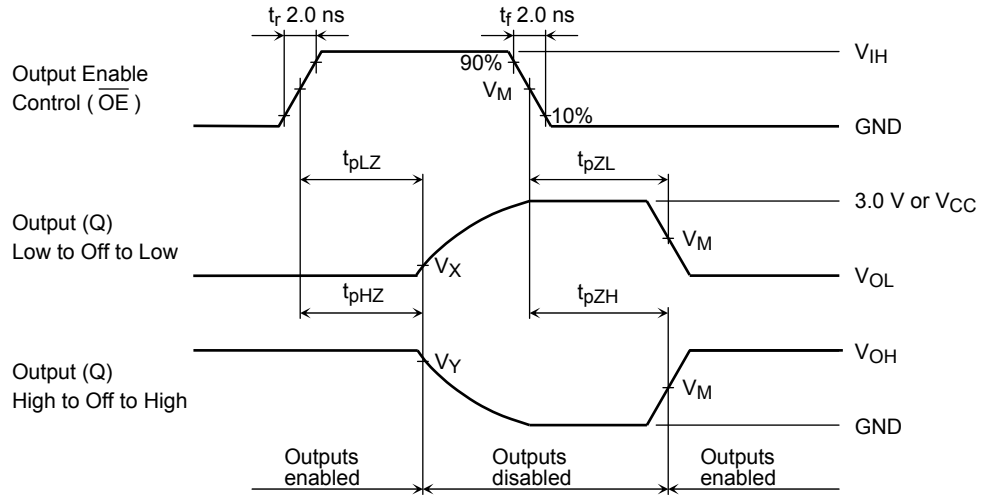


Figure 2  $t_{pLH}$ ,  $t_{pHL}$ ,  $t_w$ ,  $t_s$ ,  $t_h$



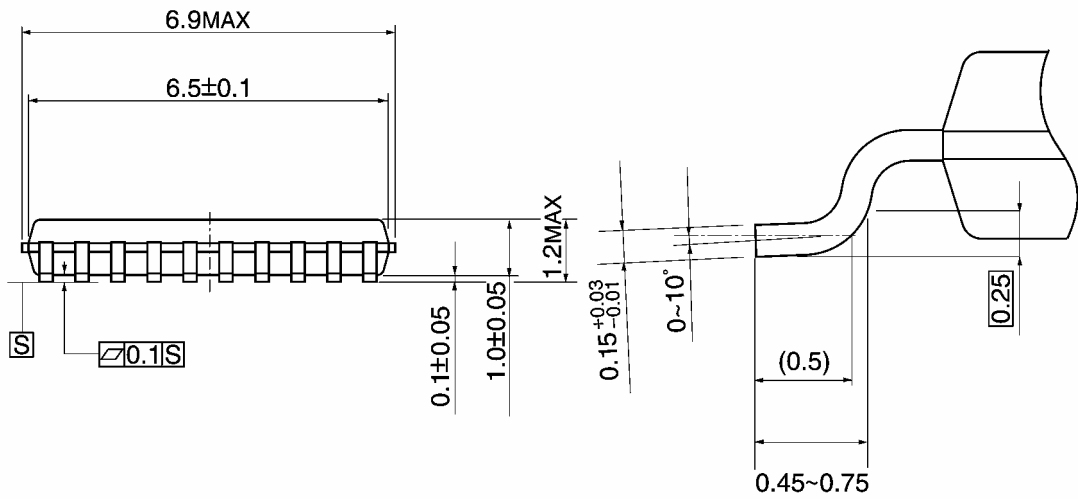
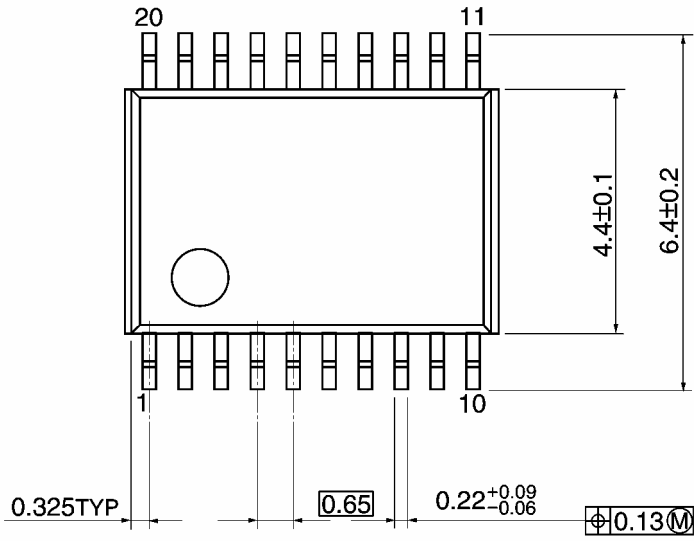
**Figure 3**  $t_{pLZ}$ ,  $t_{pHZ}$ ,  $t_{pZL}$ ,  $t_{pZH}$

Symbol	$V_{CC}$				
	$3.3 \pm 0.3\text{ V}$	$2.5 \pm 0.2\text{ V}$	$1.8 \pm 0.15\text{ V}$	$1.5 \pm 0.1\text{ V}$	$1.2\text{ V}$
$V_{IH}$	2.7 V	$V_{CC}$	$V_{CC}$	$V_{CC}$	$V_{CC}$
$V_M$	1.5 V	$V_{CC}/2$	$V_{CC}/2$	$V_{CC}/2$	$V_{CC}/2$
$V_X$	$V_{OL} + 0.3\text{ V}$	$V_{OL} + 0.15\text{ V}$	$V_{OL} + 0.15\text{ V}$	$V_{OL} + 0.1\text{ V}$	$V_{OL} + 0.1\text{ V}$
$V_Y$	$V_{OH} - 0.3\text{ V}$	$V_{OH} - 0.15\text{ V}$	$V_{OH} - 0.15\text{ V}$	$V_{OH} - 0.1\text{ V}$	$V_{OH} - 0.1\text{ V}$

**Package Dimensions**

TSSOP20-P-0044-0.65A

Unit: mm

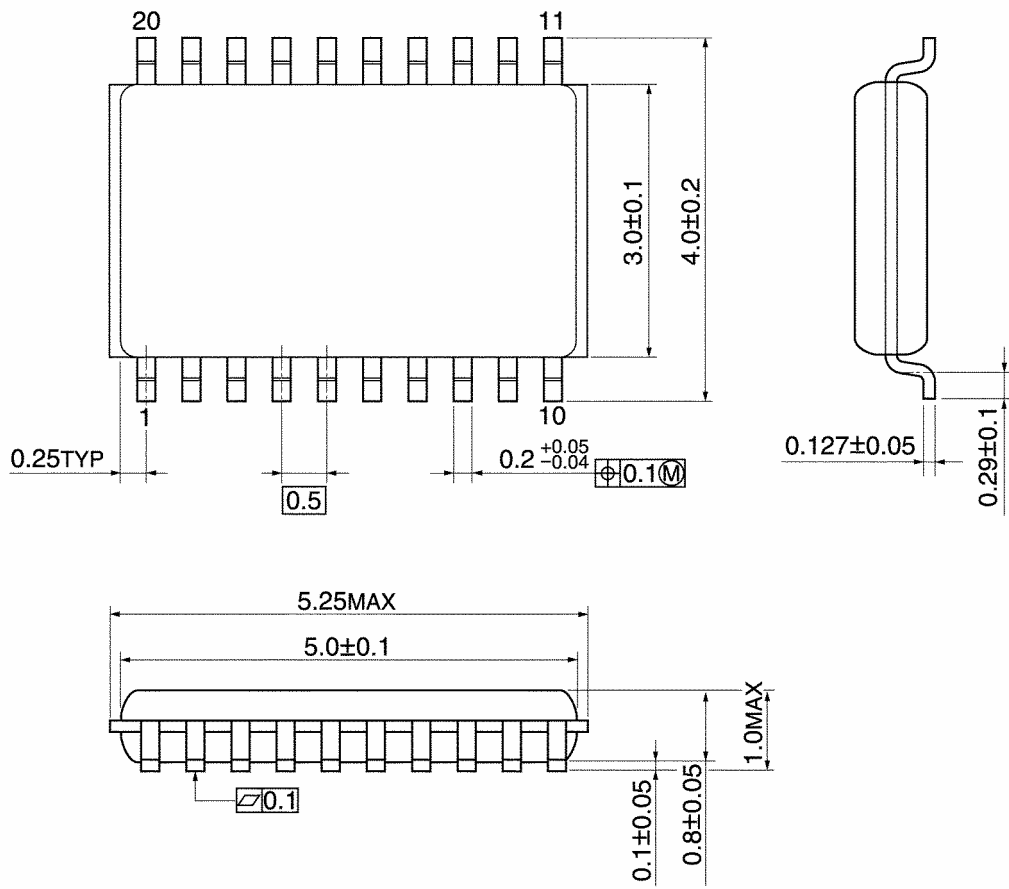


Weight: 0.08 g (typ.)

## Package Dimensions

VSSOP20-P-0030-0.50

Unit: mm



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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